Application No. 10/615,794 Docket No.: YOR920030059US1 (20140-00302-US)
Amendment dated May 8, 2006 Page 2 of 8

Reply to Final Office Action of February 8, 2006

AMENDMENTS TO THE CLAIMS

1. (Canceled).

2. (Currently amended). The method of measuring a stability of a plating bath, according to claim [[1]] 15, wherein determining a concentration of said void-formation marker comprises: separating said void-formation marker from said plating bath liquor; and quantifying said void-formation marker.

- 3. (Original). The method of measuring a stability of a plating bath, according to claim 2, wherein said void-formation-marker is separated chromatographically.
- (Original). The method of measuring a stability of a plating bath, according to claim 3, wherein said void-formation-marker is separated by liquid chromatography.
- (Original). The method of measuring a stability of a plating bath, according to claim 3, wherein said void-formation-marker is separated by high performance liquid chromatography (HPLC).
- (Original). The method of measuring a stability of a plating bath, according to claim 3, wherein said chromatography comprises ion-pairing, reversed-phase chromatography.
- 7. (Original). The method of measuring a stability of a plating bath, according to claim 2, wherein said quantifying is performed by instrumental analytical methods selected from the group consisting of spectroscopy and electrochemical detection.
- 8. (Original). The method of measuring a stability of a plating bath, according to claim 7, wherein said spectroscopy comprises techniques selected from the group consisting of ultraviolet, visible, infrared, and mass spectroscopy.

Application No. 10/615,794 Docket No.: YOR920030059US1 (20140-00302-US)
Amendment dated May 8, 2006 Page 3 of 8

Reply to Final Office Action of February 8, 2006

9. (Original). The method of measuring a stability of a plating bath, according to claim 2, wherein said quantitation is provided by instrumentation that provides a quantitative output in proportion to a concentration of said void-formation marker.

10. (Currently amended). A method of measuring a plating bath breakdown threshold value, T, said method comprising:

plating at least one metal on a substrate;

determining a plurality of time-points;

determining a VFM ratio for each of said time-points;

counting, for each of said time-points, a number of voids in the metal plated on said substrate:

determining said threshold value as the largest VFM ratio (the concentration of VFM divided by the concentration of accelerator) at which no voids are observed.

11. (Original). A method of measuring a plating bath breakdown threshold value, according to claim 10, wherein said VFM ratio is the said concentration of said void-formation marker divided by a concentration of an accelerator.

12. (Original). A method of maintaining a plating bath under non-voiding conditions, the method comprising the steps of:

determining a bath threshold value, T:

determining a CVFM; and

performing a bleed and feed to maintain said C_{VFM} below the value of said threshold.

13. (Original). A method of maintaining a plating bath under non-voiding conditions, according to claim 12, wherein said bleed and feed comprises the steps of:

adding a volume of fresh bath liquor to bring the volume to a fractional volume above a nominal bath volume; and

Application No. 10/615,794 Docket No.: YOR920030059US1 (20140-00302-US)
Amendment dated May 8, 2006 Page 4 of 8

Reply to Final Office Action of February 8, 2006

removing said fractional volume;

14. (Original). A method of maintaining a plating bath under non-voiding conditions, according to claim 13, wherein said fractional volume is from about 1% to about 10%.

15. (New). A method of measuring a stability of a plating bath, said method comprising:

measuring a plating bath breakdown threshold value, T, said measurement comprising: providing a plating bath containing at least an accelerator;

plating at least one metal on a substrate;

measuring the bath concentration of at least one accelerator breakdown product ("void-formation marker,VFM");

determining a VFM ratio at each of a plurality of time-points,

wherein said VFM ratio is the concentration of said VFM divided by the concentration of said accelerator;

counting, for each of said time-points, the number of voids in the metal plated on said substrate:

determining said threshold concentration as the largest VFM ratio at which no voids are observed; and

maintaining said VFM concentration below said threshold concentration.